

Sources of Field Perturbations

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RF System Architecture

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Sources of Field Perturbations

o Beam loading

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- Beam current fluctuations
- Pulsed beam transients
- Multipacting and field emission
- Excitation of HOMs
- Excitation of other passband modes
- Wake fields

o <u>Cavity drive signal</u>

- HV- Pulse flatness
- HV PS ripple
- Phase noise from master oscillator
- Timing signal jitter
- Mismatch in power distribution

o Cavity dynamics

- cavity filling
- settling time of field
- o Cavity resonance frequency change
- thermal effects (power dependent)
- Microphonics
- Lorentz force detuning
- o Other
 - Response of feedback system
 - Interlock trips
 - Thermal drifts (electronics, power amplifiers, cables, power transmission system)



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Cavity Deformation by Electromagnetic Field Pressure

Radiation pressure

$$P = \frac{\left(\mu_0 \left| \vec{H} \right|^2 - \varepsilon_0 \left| \vec{E} \right|^2\right)}{4}$$

Resonance frequency shift

$$\Delta f = -K \cdot E_{acc}^2$$





- Effects of Lorenz force detuning
 - Change cavity voltage and phase during RF pulse
 - Generate more reflection power
 - Limit maximum repetition rate of RF pulses
- Properties
 - Gradient dependent
 - Predictable from pulse to pulse
 - Perturbations are correlated from cavity to cavity

Measurement of Lorentz Force Detuning

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 Mechanical vibrations caused by the accelerator environment are always present and may be transferred to the cavity.





- Effects of microphonics
 - It mainly influences the resonance frequency of the cavity and therefore the RF phase with respect to the beam
- Properties
 - Slow perturbation
 - Not predictable
 - Uncorrelated along the Linac

Microphonics at JLAB

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Microphonics at FLASH

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Beam Current (Bunch Charge) Fluctuation



- Single bunch transient is not controllable
- Bunch charge fluctuation will introduce energy spread



Bunch Charge Pattern at FLASH

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Phase Noise of Master Oscillator

Phase Noise of FLASH MO

🔆 Agilent E5052A Signal Source Analyzer

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Phase Drift of 80 m 7/8" Reference Line at FLASH



Error Map

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[1] T. Schilcher. Vector Sum Control of Pulsed Accelerating Fields in Lorentz Force Detuned Superconducting Cavities. Ph.D. Thesis of DESY, 1998

[2] V. Ayvazyan, S. Simrock. Dynamic Lorenz Force Detuning Studies in TESLA Cavities. EPAC 2004, July 2004.